### 30V N-CHANNEL ENHANCEMENT MODE MOSFET

#### **SUMMARY**

 $V_{(BR)DSS}=30V; R_{DS(ON)}=0.11\Omega; I_D=3.2A$ 

#### **DESCRIPTION**

This new generation of high density MOSFETs from Zetex utilise a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.

#### **FEATURES**

- · Low on-resistance
- · Fast switching speed
- Low threshold
- Low gate drive
- SOT23-6 package

#### **APPLICATIONS**

- DC DC converters
- Power management functions
- Disconnect switches
- Motor control

### ORDERING INFORMATION

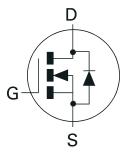
DEVICE	REEL SIZE (inches)	TAPE WIDTH (mm)	QUANTITY PER REEL
ZXM62N03E6TA	7	8mm embossed	3000 units
ZXM62N03E6TC	13	8mm embossed	10000 units

#### **DEVICE MARKING**

• 2N03



SOT23-6





Top View



### **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V <sub>DSS</sub>	30	V
Gate Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current ( $V_{GS}$ =10V; $T_A$ =25°C)(b) ( $V_{GS}$ =10V; $T_A$ =70°C)(b)	I <sub>D</sub>	3.2 2.6	А
Pulsed Drain Current (c)	I <sub>DM</sub>	18	А
Continuous Source Current (Body Diode) (b)	Is	2.1	А
Pulsed Source Current (Body Diode)	I <sub>SM</sub>	18	А
Power Dissipation at T <sub>A</sub> =25°C (a) Linear Derating Factor	P <sub>D</sub>	1.1 8.8	W mW/°C
Power Dissipation at T <sub>A</sub> =25°C (b) Linear Derating Factor	P <sub>D</sub>	1.7 13.6	W mW/°C
Operating and Storage Temperature Range	T <sub>i</sub> :T <sub>stq</sub>	-55 to +150	°C

### THERMAL RESISTANCE

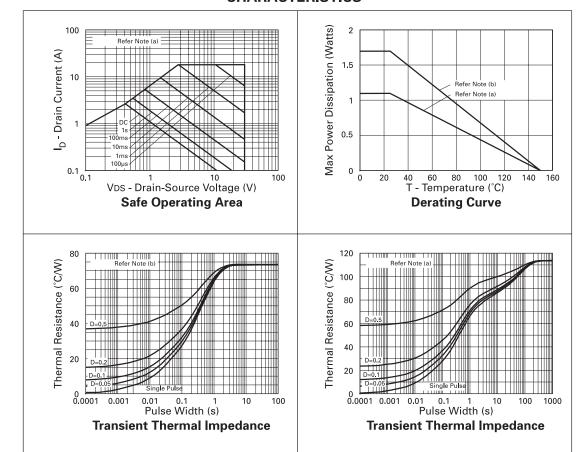
PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)	$R_{\theta JA}$	113	°C/W
Junction to Ambient (b)	$R_{\theta JA}$	73	°C/W

#### NOTES:

- (a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions
- (b) For a device surface mounted on FR4 PCB measured at t $\!\!<\!\!5$  secs.
- $(c) \ Repetitive \ rating pulse \ width \ limited \ by \ maximum \ junction \ temperature. \ Refer \ to \ Transient \ Thermal \ Impedance \ graph.$

**ZETEX**SEMICONDUCTORS

### **CHARACTERISTICS**





## **ELECTRICAL CHARACTERISTICS** (at Tamb = 25°C unless otherwise stated)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS.	
STATIC			'	'			
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	30			V	$I_D = 250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			1	μА	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V	
Gate-Body Leakage	I <sub>GSS</sub>			100	nA	V <sub>GS</sub> =( 20V, V <sub>DS</sub> =0V	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	1.0			V	$I_{D} = 250 \mu A, V_{DS} = V_{GS}$	
Static Drain-Source On-State Resistance (1)	R <sub>DS(on)</sub>			0.11 0.15	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =2.2A V <sub>GS</sub> =4.5V, I <sub>D</sub> =1.1A	
Forward Transconductance	g <sub>fs</sub>	1.1			S	V <sub>DS</sub> =10V,I <sub>D</sub> =1.1A	
DYNAMIC (3)		•		•	•		
Input Capacitance	C <sub>iss</sub>		380		pF	V <sub>DS</sub> =25 V, V <sub>GS</sub> =0V, f=1MHz	
Output Capacitance	C <sub>oss</sub>		90		pF		
Reverse Transfer Capacitance	C <sub>rss</sub>		30		pF	1	
SWITCHING(2) (3)		•		•			
Turn-On Delay Time	t <sub>d(on)</sub>		2.9		ns		
Rise Time	t <sub>r</sub>		5.6		ns	$V_{DD} = 15V, I_{D} = 2.2A$	
Turn-Off Delay Time	t <sub>d(off)</sub>		11.7		ns	$R_{G}=6.0\Omega$ , $R_{D}=6.7\Omega$ (refer to test circuit)	
Fall Time	t <sub>f</sub>		6.4		ns		
Total Gate Charge	Qg			9.6	nC	V <sub>DS</sub> =24V,V <sub>GS</sub> =10V, I <sub>D</sub> =2.2A (refer to test circuit)	
Gate-Source Charge	Q <sub>gs</sub>			1.7	nC		
Gate Drain Charge	Q <sub>gd</sub>			2.8	nC		
SOURCE-DRAIN DIODE		•	'	<b>'</b>			
Diode Forward Voltage (1)	V <sub>SD</sub>			0.95	V	$T_j = 25$ °C, $I_S = 2.2$ A, $V_{GS} = 0$ V	
Reverse Recovery Time (3)	t <sub>rr</sub>		18.8		ns	T <sub>j</sub> =25°C, I <sub>F</sub> =2.2A,	
Reverse Recovery Charge (3)	Q <sub>rr</sub>		11.4		nC	di/dt= 100A/μs	

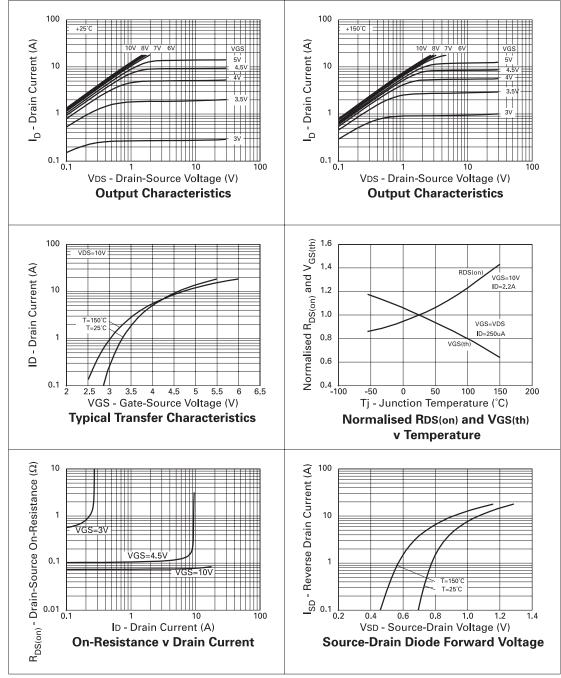
<sup>(1)</sup> Measured under pulsed conditions. Width=300 $\mu s.$  Duty cycle @2% .

ZETEX SEMICONDUCTORS

<sup>(2)</sup> Switching characteristics are independent of operating junction temperature.

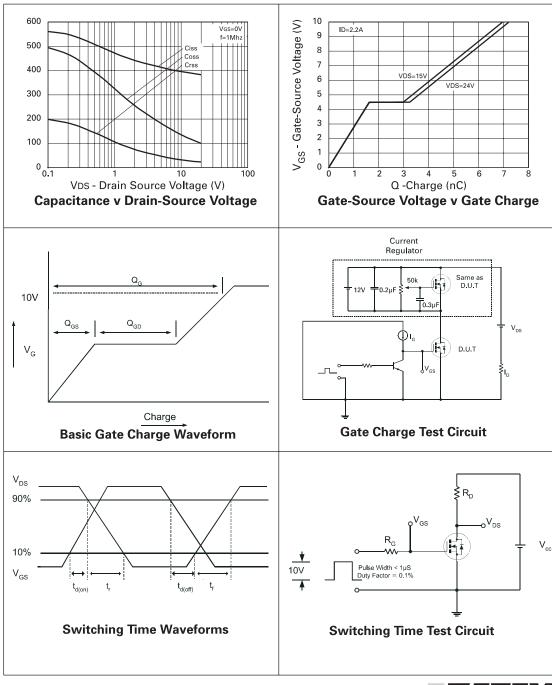
<sup>(3)</sup> For design aid only, not subject to production testing.

### **TYPICAL CHARACTERISTICS**





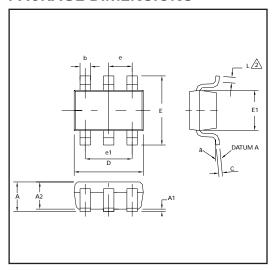
### TYPICAL CHARACTERISTICS





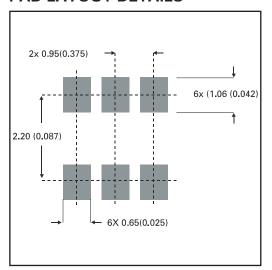
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### **PACKAGE DIMENSIONS**



DIM	Millimeters		Inches		
	Min	Max	Min	Max	
Α	0.90	1.45	0.35	0.057	
A1	0.00	0.15	0	0.006	
A2	0.90	1.30	0.035	0.051	
b	0.35	0.50	0.014	0.019	
С	0.09	0.20	0.0035	0.008	
D	2.80	3.00	0.110	0.118	
Е	2.60	3.00	0.102	0.118	
E1	1.50	1.75	0.059	0.069	

### PAD LAYOUT DETAILS



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Europe	Americas	Asia Pacific	Corporate Headquarters
Zetex GmbH	Zetex Inc	Zetex (Asia) Ltd	Zetex plc
Streitfeldstraße 19	700 Veterans Memorial Hwy	3701-04 Metroplaza Tower 1	Lansdowne Road, Chadderton
D-81673 München	Hauppauge, NY 11788	Hing Fong Road, Kwai Fong	Oldham, OL9 9TY
Germany	USA	Hong Kong	United Kingdom
Telefon: (49) 89 45 49 49 0	Telephone: (1) 631 360 2222	Telephone: (852) 26100 611	Telephone (44) 161 622 4444
Fax: (49) 89 45 49 49 49	Fax: (1) 631 360 8222	Fax: (852) 24250 494	Fax: (44) 161 622 4446
europe.sales@zetex.com	usa.sales@zetex.com	asia.sales@zetex.com	hq@zetex.com

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